

N85-32419

# MEASURING BULK RECOMBINATION RATES AND BOUNDARY RECOMBINATION VELOCITIES

UNIVERSITY OF PENNSYLVANIA

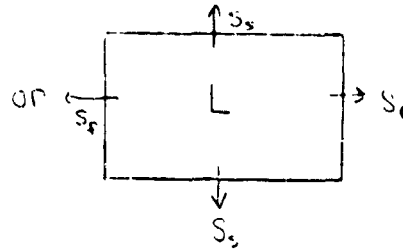
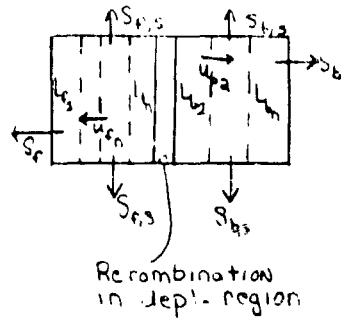
M. Wolf

## Measurement of $L$ (or $\tau$ ) and $s$

- I. ALL METHODS MEASURE SOME OTHER QUANTITY, DEDUCE  $L$  (OR  $\tau$ ) AND  $s$ .
- II. IN MOST, THE MEASURED QUANTITY IS ALSO INFLUENCED BY OTHER PARAMETERS. THESE ARE SEPARATELY MEASURED, ASSUMED, OR NEGLECTED.
- III. ALL METHODS HAVE RANGES OF  $L$ ,  $s$ , OR THE OTHER PARAMETERS, WHERE THE DEPENDENCE OF THE MEASURED QUANTITY ON  $L$  AND/OR  $s$  IS WEAK.
- IV. THERE ARE STEADY-STATE AND TIME-DEPENDENT MEASUREMENTS. SOME OF THE LATTER STILL DEPEND ON A TRANSPORT PROPERTY ( $L$ ), NOT A TIME CONSTANT ( $\tau$ ).
- V. SOME METHODS FIND A CONDITION WHERE THE MATHEMATICAL RELATIONSHIPS BECOME SIMPLE, F.G. REAL AND IMAGINARY PARTS OF A NUMBER BECOME EQUAL.

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# HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH



MEASURED QUANTITY:

	$M = M(L_{WANTED}, u_{WANTED}, A_1 \dots A_I, B_1 \dots B_J, C_1 \dots C_K, D_1 \dots D_N)$				
MAY BE COMPLEX NUMBER		VARIABLE DEVICE PARAMETERS	VARIABLE EXTERNAL PARAMETERS	CONSTANT DEVICE PARAMETERS	CONSTANT EXTERNAL PARAMETERS
EXAMPLE:	$L_{FI}$	$u_{FI} \pm 1$	THICKNESSES $S_{BJ}, S_{FJ}, L_{BJ}, L_{FJ}, u_{FJ}, u_{BJ}$	T S-INFLUENCING ENV'T EXCITATION: LIGHT: $\lambda, f$ VOLTAGE: $V_1, f$ TERMINAL IMPEDANCE: s.c., o.c., ETC.	ANY OF $B_1$ NOT VARIED; R IN DEPL'N REGION

## Basic Requirement for Determination of Both L and u

AT LEAST 2 INDEPENDENT MEASURED DATA ( $M_1, M_2$ ) NEEDED,  
WHICH ARE SENSITIVE TO U AND L IN THEIR RANGE OF INTEREST.  
(ONE MEASUREMENT MAY BE SENSITIVE TO ONLY L OR U, IF THE OTHER IS SENSITIVE TO BOTH.)

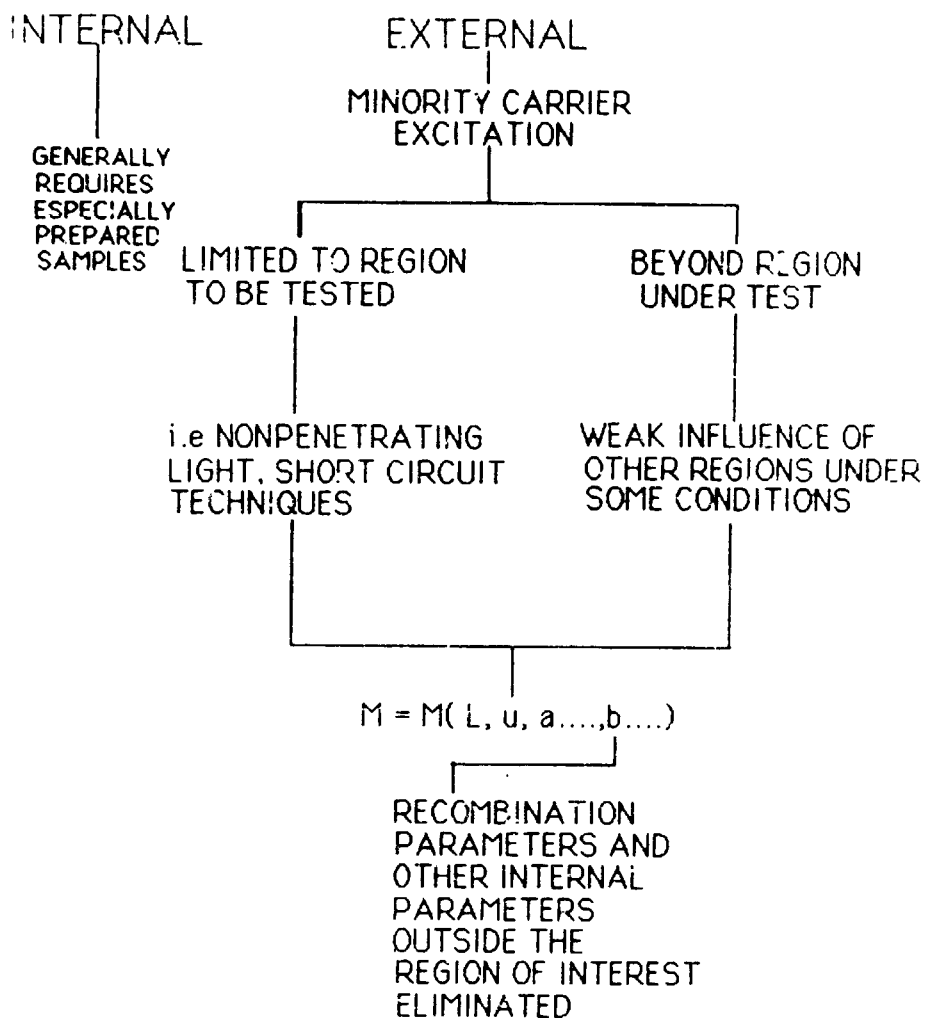
2 INDEPENDENT DATA ARE AVAILABLE FROM:

- COMPLEX NUMBERS (ONE OPTION)
- VARIATION OF A SUITABLE PARAMETER (EACH PARAMETER = ONE OPTION)

FIND: A SENSITIVE DATA PAIR SEEMS THE MORE LIKELY, THE MORE OPTIONS FOR OBTAINING 2 DATA POINTS EXIST.

# HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH

## Type of Parameters Varied



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## Classification of Methods

TYPE	EXCITATION	M	VARIED EXTERNAL PARAMETERS	NUMBER OF OPTIONS
ASLBIC	LIMITABLE	REAL	$\lambda$	1
MODULATED LIGHT METHOD	LIMITABLE	COMPLEX	$\omega, \lambda$	3
IMPEDANCE	DEVICE DEPENDENT	COMPLEX	$\omega$	2
$I_{sc} \cdot V_{DC}$ PAIR	DEVICE DEPENDENT	COMPLEX	CIRCUIT IMPEDENCE	1
SCCD	DEVICE DEPENDENT	REAL	CIRCUIT IMPEDENCE	1

## HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH

**Goal: Reduce the Number of Variable or Constant Parameters  
(Requirements Listed in Order of Importance):**

1. ELIMINATE INFLUENCE OF UNMEASURABLE PARAMETERS.
2. FIND SENSITIVE RELATIONSHIP BETWEEN  $L_{\text{WANTED}}$ ,  $U_{\text{WANTED}}$  AND M.
3. METHOD SHOULD BE APPLICABLE TO FINISHED, OR IN-PROCESS PRODUCT.
4. FIND EASILY MEASURABLE QUANTITY M, AND EASILY, REPEATABLY VARIABLE PARAMETERS.
5. REDUCE NUMBER OF INFLUENCING PARAMETERS.
6. FIND SIMPLE RELATIONSHIP.

### The Basic Carrier Diffusion Expression

AN EXAMPLE FOR M: (ASLBIC):

$$M = \tau_{\text{COLL}} = \frac{B}{B+Y} E^{-B} \left\{ 1 + \frac{1}{B-Y} \frac{(1+A) Y E^{-Y}}{\cosh Y} - \frac{(B+A) E^B}{A \sinh A} \right\}$$

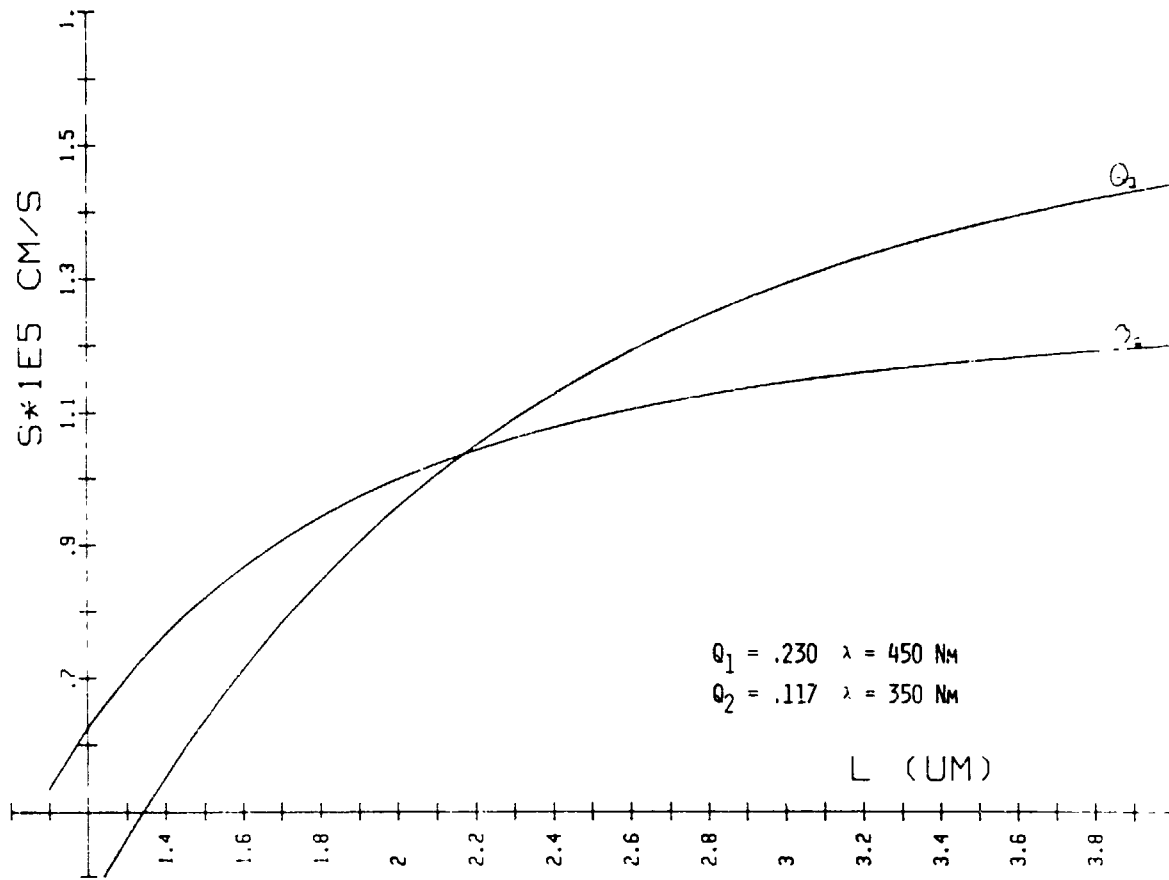
(SIMPLEST FORM FOR SINGLE-LAYER FRONT REGION)

WITH THE BASIC VARIABLES:

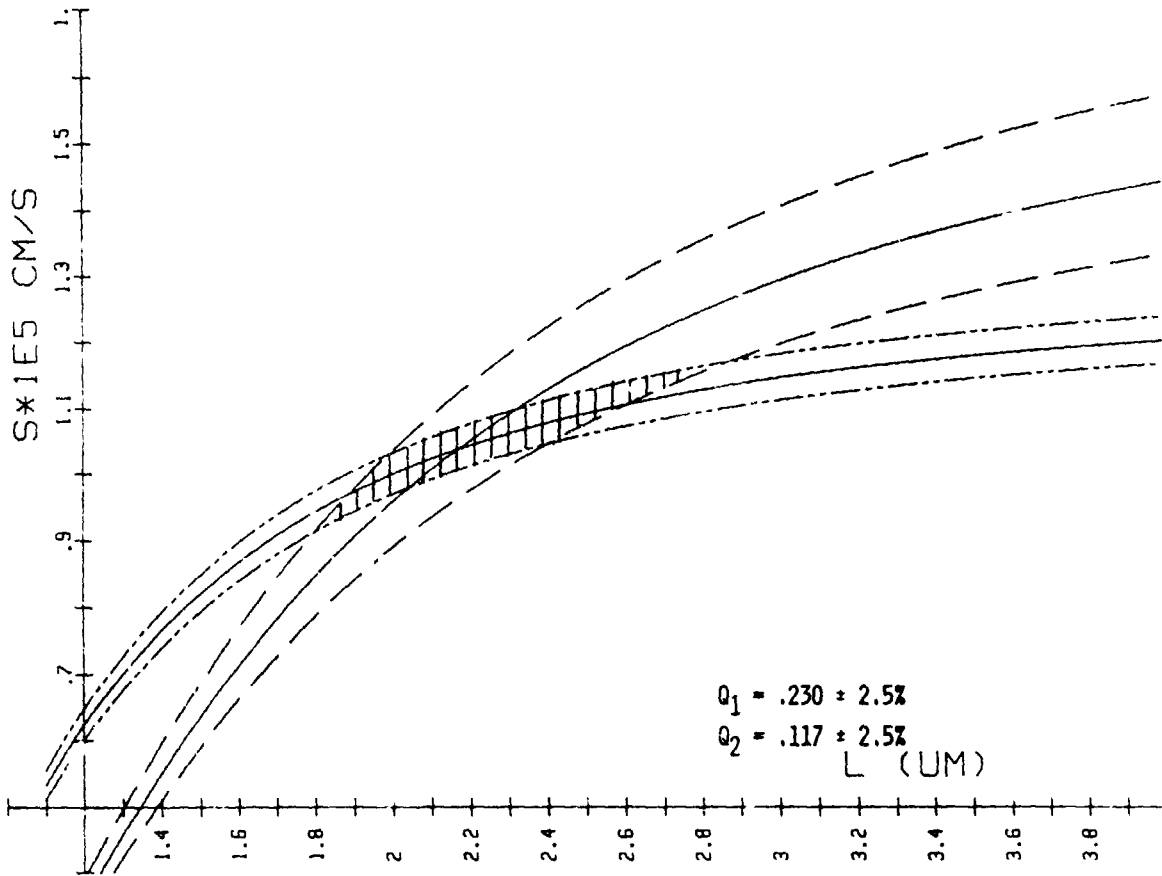
$$Y = \frac{X}{L} \sqrt{E}; \quad A = \frac{S}{D}; \quad B = \alpha(\lambda) \cdot X \cdot J \cdot F$$

VERY SIMILAR RELATIONSHIPS FOR OTHER METHODS.

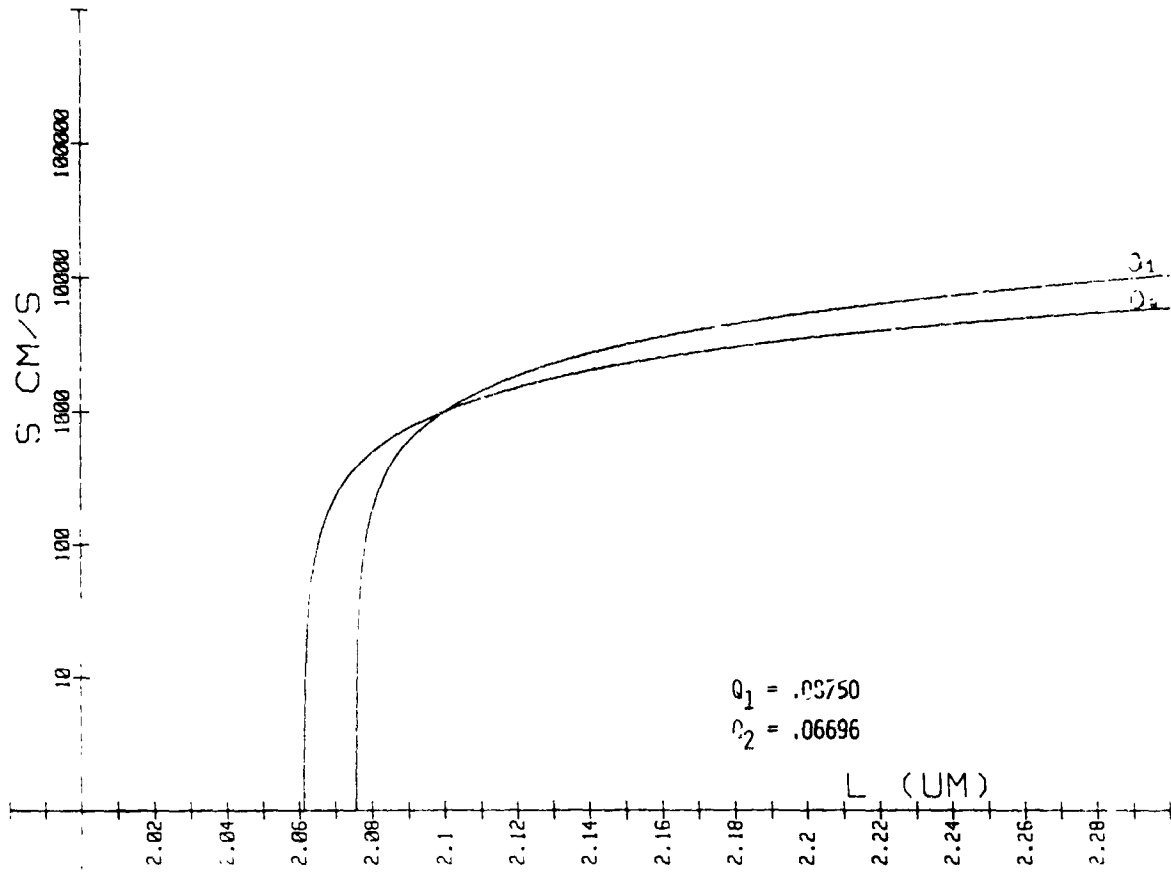
# HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH



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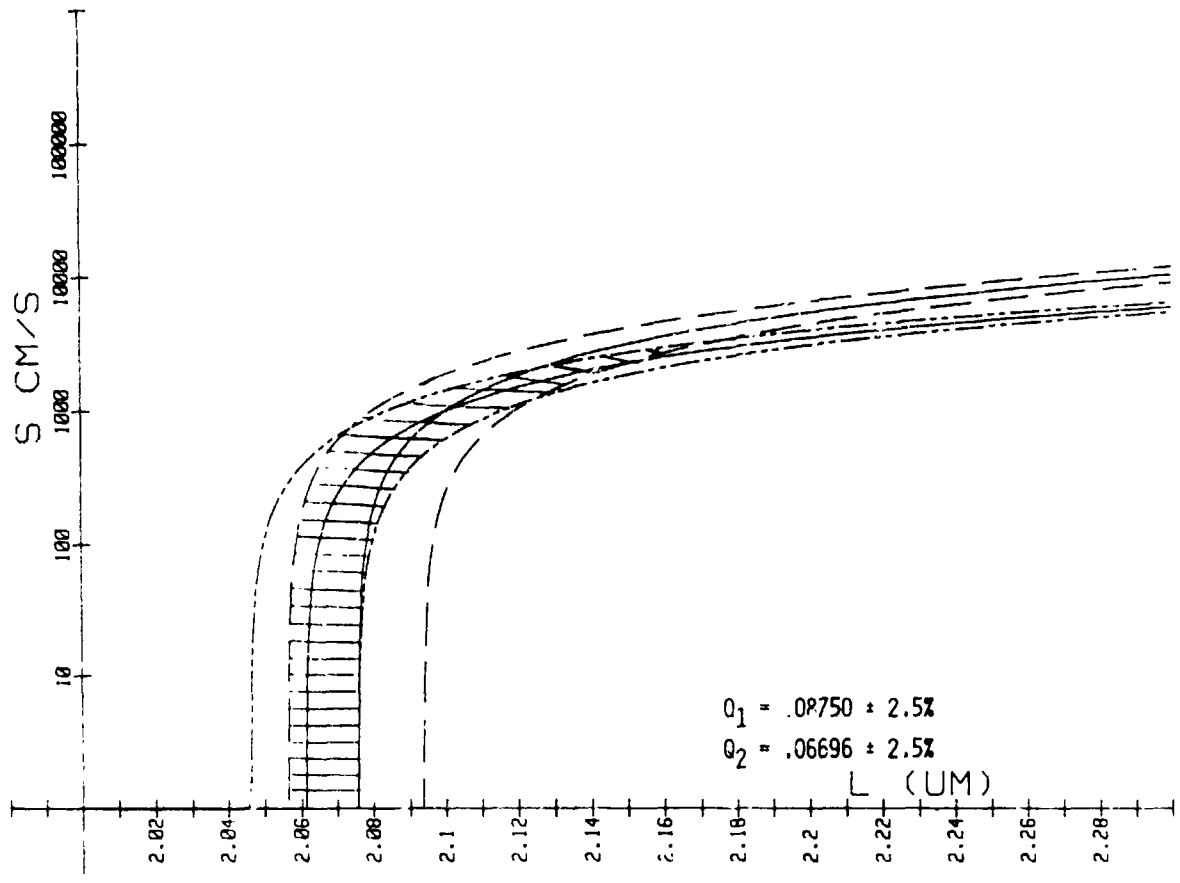


# HIGH-EFFICIENCY SILICON SOLAR CELL RESEARCH





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## Measurement Comparison Criterion

SENSITIVITY ANALYSIS DETERMINES THE ERRORS IN CONSEQUENCE OF INACCURACIES IN THE MEASURED DATA AND THE PARAMETERS.

EXAMPL. ASLBIC:

$$M_1 = M(L, S, \lambda_1, A_2 \dots) \quad (1)$$

$$M_2 = M(L, S, \lambda_2, A_2 \dots) \quad (2)$$

IDEALLY, THESE EQUATIONS WOULD BE ANALYTICALLY INVERTIBLE TO:

$$S = S(M_1, M_2, \lambda_1, \lambda_2, A_2 \dots, B_1 \dots) \quad (3)$$

$$L = L(M_1, M_2, \lambda_1, \lambda_2, A_2 \dots, B_1 \dots) \quad (4)$$

AND THEN PERMIT A SENSITIVITY ANALYSIS SUCH AS:

$$\Delta S = \left. \frac{\partial S}{\partial M_1} \right|_{M_2} \Delta M_1 + \left. \frac{\partial S}{\partial M_2} \right|_{M_1} \Delta M_2 \quad (5)$$

$$\Delta L = \left. \frac{\partial L}{\partial M_1} \right|_{M_2} \Delta M_1 + \left. \frac{\partial L}{\partial M_2} \right|_{M_1} \Delta M_2 \quad (6)$$

AS EQ. (1), (2) ARE TRANSCENDENTAL (3), (4) ARE NOT ANALYTICALLY EXPRESSABLE.

HOWEVER:

$$S = S(L, M, \lambda, A_2 \dots, B_1 \dots)$$

IS AVAILABLE, AND CONSEQUENTLY (6). FOR (5), NOTE

$$\left. \frac{\partial S}{\partial M_1} \right|_{M_2} \neq \left. \frac{\partial M}{\partial S} \right|_L$$

WHERE ANALYTICAL TREATMENT NOT POSSIBLE, LINEAR APPROXIMATIONS:

$$M_1 = M_0(S_F, L_F, A_1 \dots) + \left. \frac{\partial M}{\partial A_1} \right|_{S_F, L_F \dots} \Delta A_{1,1}$$

$$M_2 = M_0(S_F, L_F, A_1 \dots) + \left. \frac{\partial M}{\partial A_1} \right|_{S_F, L_F \dots} \Delta A_{1,2}$$

$$M_3 = M_1 + \left. \frac{\partial M}{\partial S_F} \right|_{L_F, A_1 + \Delta A_{1,1} \dots}$$

MAY YIELD SOME INFORMATION ON SENSITIVE RANGES.